

FDS7088N7

30V N-Channel PowerTrench® MOSFET

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low R_{DS(ON)} in a small package.

Applications

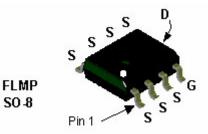
· Synchronous rectifier

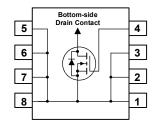
SO-8

• DC/DC converter

Features

- 23 A, 30 V $R_{DS(ON)} = 3 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 4 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability
- · Fast switching
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±20	
I _D	Drain Current - Continuous	(Note 1a)	23	Α
	– Pulsed		60	
P _D	Power Dissipation for Single Operation	(Note 1a)	3.0	W
		(Note 1b)	1.5	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	

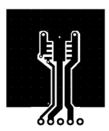
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS7088N7	FDS7088N7	13"	12mm	2500 units

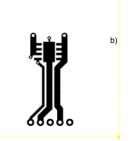
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	30			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			10	μА
I_{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Chara	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1	1.9	3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-6		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, \qquad I_D = 23 \text{ A} $ $V_{GS} = 4.5 \text{ V}, \qquad I_D = 21 \text{ A} $ $V_{GS} = 10 \text{ V}, \qquad I_D = 23 \text{ A}, T_J = 125^{\circ}\text{C}$		2.4 3.3 3.5	3 4 5.5	mΩ
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 23 \text{ A}$		112		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	V _{DS} = 15 V, V _{GS} = 0 V,		3845		pF
Coss	Output Capacitance	f = 1.0 MHz		930		pF
C _{rss}	Reverse Transfer Capacitance			368		pF
R_{G}	Gate Resistance	$V_{GS} = 15 \text{ mV}, f = 1.0 \text{ MHz}$		1.4		Ω
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		15	27	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		13	23	ns
$t_{d(off)}$	Turn-Off Delay Time			62	99	ns
t _f	Turn-Off Fall Time			36	58	ns
Q_g	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 23 \text{ A},$		37	48	nC
Q_{gs}	Gate-Source Charge	$V_{GS} = 5.0 \text{ V}$		10		nC
Q_{gd}	Gate-Drain Charge			14		nC
Drain-Sc	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	e Diode Forward Current			2.5	Α
V_{SD}	Drain–Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.5 A (Note 2)		0.7	1.2	V
t _{rr}	Diode Reverse Recovery Time	I _F = 23 A,		39		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$		33		nC

Notes:

1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a) 40°C/W when mounted on a 1in² pad of 2 oz copper



85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

Typical Characteristics

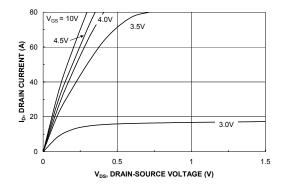


Figure 1. On-Region Characteristics.

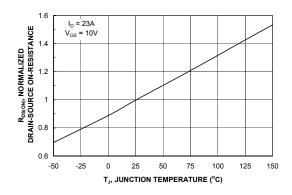


Figure 3. On-Resistance Variation with Temperature.

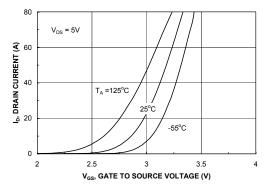


Figure 5. Transfer Characteristics.

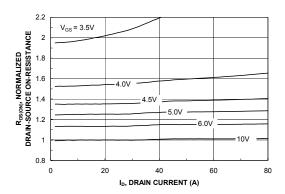


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

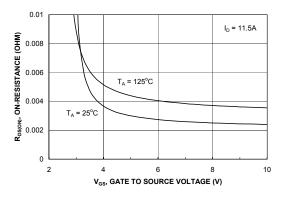


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

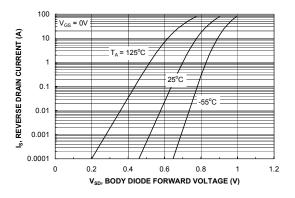
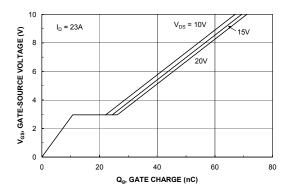


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



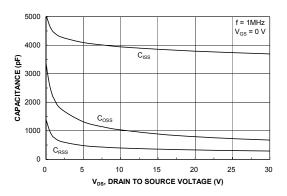


Figure 7. Gate Charge Characteristics.

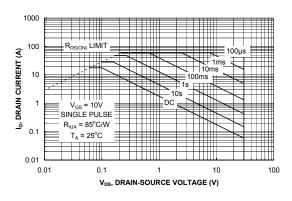


Figure 8. Capacitance Characteristics.

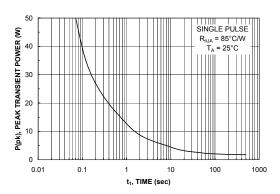


Figure 9. Maximum Safe Operating Area.



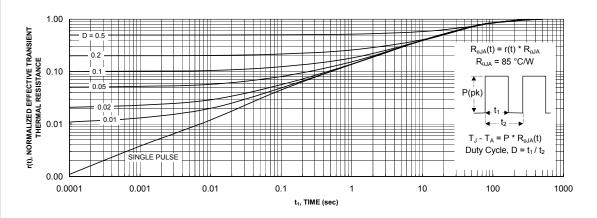
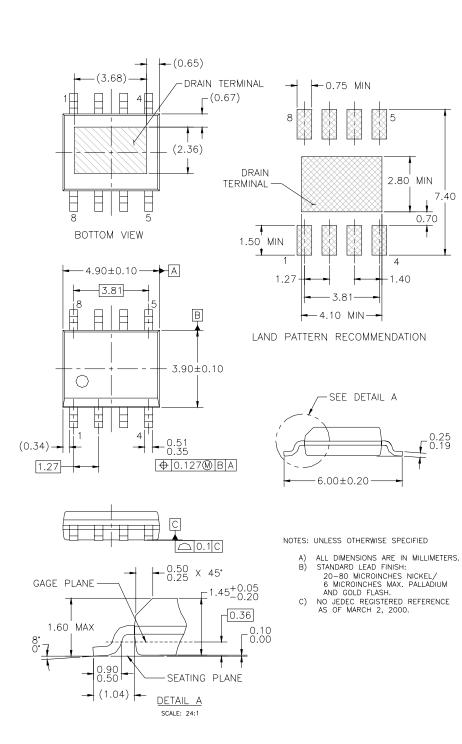


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

Dimensional Outline and Pad Layout



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